

**Search Notes**

Application/Control No.

10/747,969

Examiner

Y. J. Han

**Applicant(s)/Patent under Reexamination**

PERON ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
363	78		
	81		
	87		
	125		
	126		
	127		
	44		
315	307		
	308	9/05	YJH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	9/05	YJH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner